

TDSEMIC

拓 電 半 導 體

自主封測 品質把控 售後保障

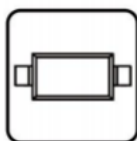
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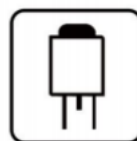
電源管理



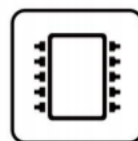
顯示驅動



二三極管



LDO穩壓器



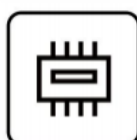
觸摸芯片



MOS管



運算放大器



存儲芯片



MCU



串口通信

3401A-TD

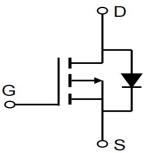
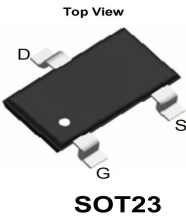
產品規格說明書

Features

- 30V, -4A
 $R_{DS(ON)} < 73m\Omega @ V_{GS} = -4.5V$
 $R_{DS(ON)} < 98m\Omega @ V_{GS} = -2.5V$
- Advanced Trench Technology
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- Lead Free

Applications

- Load Switch
- PWM Application
- Power Management



Absolute Maximum Ratings (@ $T_A = 25^{\circ}C$ unless otherwise specified)

Symbol	Parameter	Value	Units
V_{DS}	Drain-to-Source Voltage	-30	V
V_{GS}	Gate-to-Source Voltage	± 12	V
I_D	Continuous Drain Current	$T_A = 25^{\circ}C$	A
		$T_A = 100^{\circ}C$	
I_{DM}	Pulsed Drain Current ⁽¹⁾	-16	A
P_D	Power Dissipation	$T_A = 25^{\circ}C$	W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽²⁾	108	$^{\circ}C/W$
T_J, T_{STG}	Junction & Storage Temperature Range	-55 to 150	$^{\circ}C$

Electrical Characteristics (T_J = 25°C unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
V _{(BR)DSS}	Drain-Source Breakdown Voltage	I _D = -250μA, V _{GS} = 0V	-30	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -30V, V _{GS} = 0V	-	-	1.0	μA
I _{GSS}	Gate-Body Leakage Current	V _{DS} = 0V, V _{GS} = ±12V	-	-	±100	nA
On Characteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = -250μA	-0.3	-0.95	-1.5	V
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽³⁾	V _{GS} = -4.5V, I _D = -3A	-	60	73	mΩ
		V _{GS} = -2.5V, I _D = -3A	-	75	98	mΩ
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{GS} = 0V, V _{DS} = -15V, f = 1MHz	-	553	-	pF
C _{oss}	Output Capacitance		-	57	-	pF
C _{rss}	Reverse Transfer Capacitance		-	35	-	pF
Q _g	Total Gate Charge	V _{GS} = 0 to -4.5V V _{DS} = -15V, I _D = -3A	-	6.5	-	nC
Q _{gs}	Gate Source Charge		-	1.4	-	nC
Q _{gd}	Gate Drain("Miller") Charge		-	1.7	-	nC
Switching Characteristics						
t _{d(on)}	Turn-On DelayTime	V _{GS} = -4.5V, V _{DD} = -15V I _D = -3A, R _{GEN} = 3Ω	-	10	-	ns
t _r	Turn-On Rise Time		-	86	-	ns
t _{d(off)}	Turn-Off DelayTime		-	150	-	ns
t _f	Turn-Off Fall Time		-	357	-	ns
Drain-Source Diode Characteristics and Max Ratings						
I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	-4	A
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-16	A
V _{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0V, I _S = -4A	-	-	-1.2	V
t _{rr}	Body Diode Reverse Recovery Time	I _F = -3A, di/dt = 80A/us	-	36	-	ns
Q _{rr}	Body Diode Reverse Recovery Charge		-	5	-	nC

- Notes:
1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
 2. R_{θJA} is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB
 3. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 0.5%.

Test Circuit

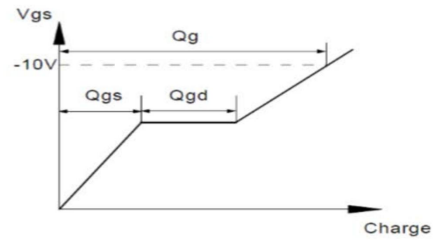
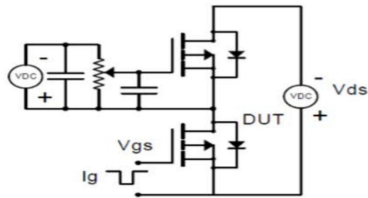


Figure 1: Gate Charge Test Circuit & Waveform

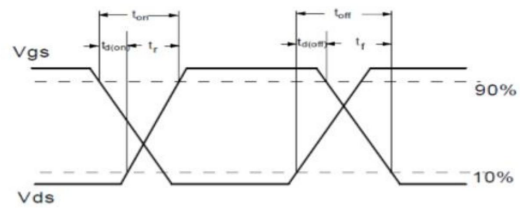
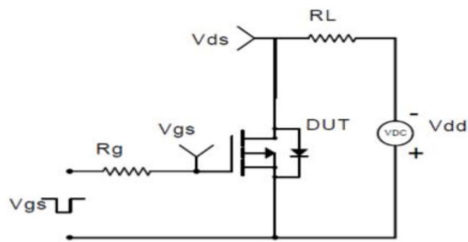


Figure 2: Resistive Switching Test Circuit & Waveform

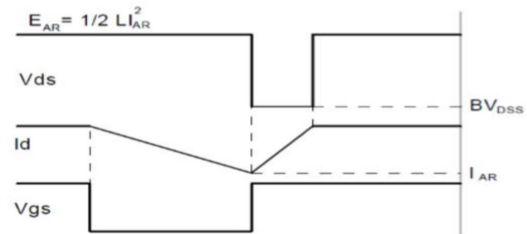
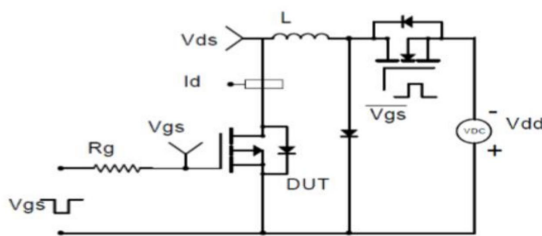


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

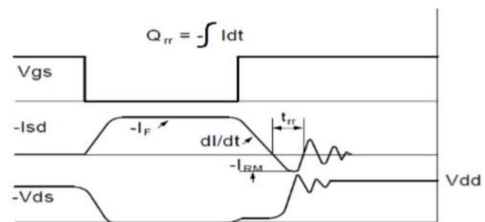
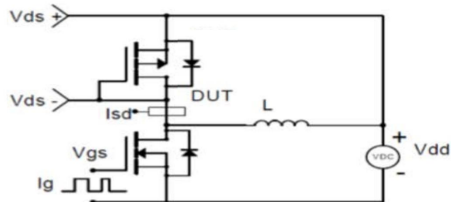
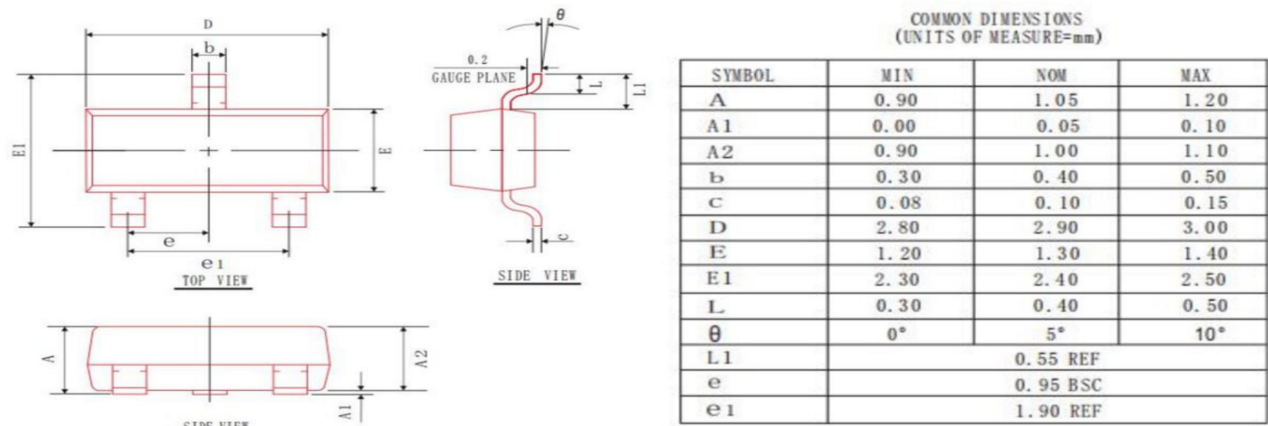


Figure 4: Diode Recovery Test Circuit & Waveform

Package Mechanical Data(SOT-23)



Recommended Footprint

